

**AMENDMENTS TO THE CLAIMS**

The following is a complete listing of revised claims with a status identifier in parenthesis.

**LISTING OF CLAIMS**

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- B1 1. (Currently Amended) An RF probe, comprising:
- a conductive return;
  - an insulator having a contact surface;
  - a probe conductor adjacent to the insulator ; and
  - a termination electrically positioned between the conductive return and the probe conductor, wherein the probe conductor is equidistant with the insulator along the entire contact surface.
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- B2 2. (Original) The RF probe of claim 1, wherein the conductive return is a ground return.
3. (Original) The RF probe of claim 1, wherein the termination is a resistor.
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- B3 4. (Previously Amended) The RF probe of claim 3, wherein the probe conductor is formed within a coaxial conductor and the termination is approximately 50 ohms.
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b4 5. (Original) The RF probe of claim 1, wherein the termination is a semiconductor device.

6. (Original) The RF probe of claim 5, wherein the termination is a diode.

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b5 7. (Currently Amended) An RF probe, comprising:  
a conductive return;  
a probe conductor within an insulator, the insulator having a contact surface; and  
a termination electrically positioned between the conductive return and the probe conductor, wherein the probe conductor is equidistant with the insulator along the entire contact surface.

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b6 8. (Original) The RF probe of claim 7, wherein the conductive return is a ground return.

9. (Original) The RF probe of claim 7, wherein the termination is a resistor.

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b7 10. (Previously Amended) The RF probe of claim 9, wherein the probe conductor is formed within a coaxial conductor and the termination is approximately 50 ohms.

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11. (Original) The RF probe of claim 7, wherein the termination is a semiconductor device.

12. (Original) The RF probe of claim 11, wherein the termination is a diode.

BB 13. (Original) The RF probe of claim 7, wherein the insulator has at least a partial cross section that is substantially circular in a plane substantially perpendicular to the probe conductor.

14. (Original) The RF probe of claim 13, wherein the conductive return is a ground return.

15. (Original) The RF probe of claim 13, wherein the termination is a resistor.

BH 16. (Previously Amended) The RF probe of claim 15, wherein the termination is approximately 50 ohms.

BFO 17. (Original) The RF probe of claim 13, wherein the termination is a semiconductor device.

B10  
end

18. (Original) The RF probe of claim 17, wherein the termination is a diode.

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19. (Currently Amended) An RF probe, comprising:

a conductive return;

B11

a probe conductor positioned within an insulator having a contact surface, the probe conductor being curved and the insulator having at least a partial cross section that is substantially circular in a plane substantially perpendicular to the probe conductor; and

a termination electrically positioned between the conductive return and the probe conductor, wherein the probe conductor is equidistant with the insulator along the entire contact surface.

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B12

20. (Previously Added) The RF probe of claim 19, wherein the probe conductor is equidistant with an RF source along the contact surface.

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